
Bringing up the BlueNRG-1 device

Introduction

The BlueNRG-1 device is a high performance, ultra-low power wireless system-on-chip which supports Bluetooth low energy specifications.

In order to achieve maximum performance, some procedures must be carried out before finalizing the application.

This document summarizes these fundamental steps:

- Application PCB test points
- Power supply and current consumption tests
- Device configuration
- XTAL and LSOSC centering tests
- Output power test
- Packet exchange test
- Sensitivity test
- Power consumption in advertising mode

Contents

1 Application PCB test points 7

2 Power supply test..... 8

 2.1 Test case specification identifier 8

 2.2 Test prerequisite 8

 2.3 Test description..... 8

 2.4 Test procedure 8

 2.5 Expected results..... 8

 2.6 Note 8

 2.7 Other 8

3 Device configuration 9

 3.1 HS_Startup_Time: Test case specification identifier 10

 3.2 Test prerequisite 10

 3.3 Test description..... 10

 3.4 Test setup 10

 3.4.1 Hardware 10

 3.4.2 Software 10

 3.5 Test procedure 10

 3.6 Expected results..... 11

 3.7 Note 11

 3.8 Other 11

4 XTAL centering test..... 12

 4.1 Test case specification identifier 12

 4.2 Test prerequisite 12

 4.3 Test description..... 12

 4.4 Test setup 12

 4.4.1 Hardware 12

 4.4.2 Software 12

 4.5 Test procedure 12

 4.6 Expected results..... 13

 4.7 Note 13

 4.8 Other 13

5 LSOSC centering test..... 14

 5.1 Test case specification identifier 14



5.2	Test prerequisite	14
5.3	Test description	14
5.4	Test setup	14
5.4.1	Hardware	14
5.4.2	Software	14
5.5	Test procedure	14
5.6	Expected results.....	14
5.7	Note	15
5.8	Other	15
6	Output power test.....	16
6.1	Test case specification identifier	16
6.2	Test prerequisite	16
6.3	Test description	16
6.4	Test setup	16
6.4.1	Hardware	16
6.4.2	Software	16
6.5	Test procedure	16
6.6	Expected results.....	16
6.7	Note	17
6.8	Other	17
7	Packet exchange test	19
7.1	Test case specification identifier	19
7.2	Test prerequisite	19
7.3	Test description	19
7.4	Test setup	19
7.4.1	Hardware	19
7.4.2	Software	19
7.5	Test procedure	19
7.6	Expected results.....	20
7.7	Note	20
7.8	Other	20
8	Sensitivity test	21
8.1	Test case specification identifier	21
8.2	Test prerequisite	21

8.3	Test description	21
8.4	Test setup	21
8.4.1	Hardware	21
8.4.2	Software	21
8.5	Test procedure	21
8.5.1	Signal generator & DUT board	21
8.5.2	ST BlueNRG-1 demo kit & DUT board.....	22
8.6	Expected results.....	23
8.7	Note	23
8.8	Other	23
9	Power consumption in advertising mode	24
9.1	Test case specification identifier	24
9.2	Test prerequisite	24
9.3	Test description.....	24
9.4	Test setup	24
9.4.1	Hardware	24
9.4.2	Software	24
9.5	Test procedure	24
9.6	Expected results.....	24
9.7	Note	25
9.8	Other	25
10	RF tests for certification	26
10.1	Signaling mode	26
10.2	Non-signaling mode	27
11	RF tests for boards manufacturing	29
12	References	30
13	Revision history	31

List of tables

Table 1: Test points7
Table 2: Supply test results8

List of figures

Figure 1: UFL connector	7
Figure 2: BlueNRG GUI IFR tool used for the device configuration	9
Figure 3: XTAL_startup measurement.....	11
Figure 4: Frequency tone at Ch0 for the XTAL center test.....	13
Figure 5: Output power measurement in with PA_level 7	17
Figure 6: Output power measurement in High power mode with PA_level 6	18
Figure 7: Typical current profile during an advertising event.....	25
Figure 8: Signaling mode RF tests	27
Figure 9: Non-signaling mode RF tests	28

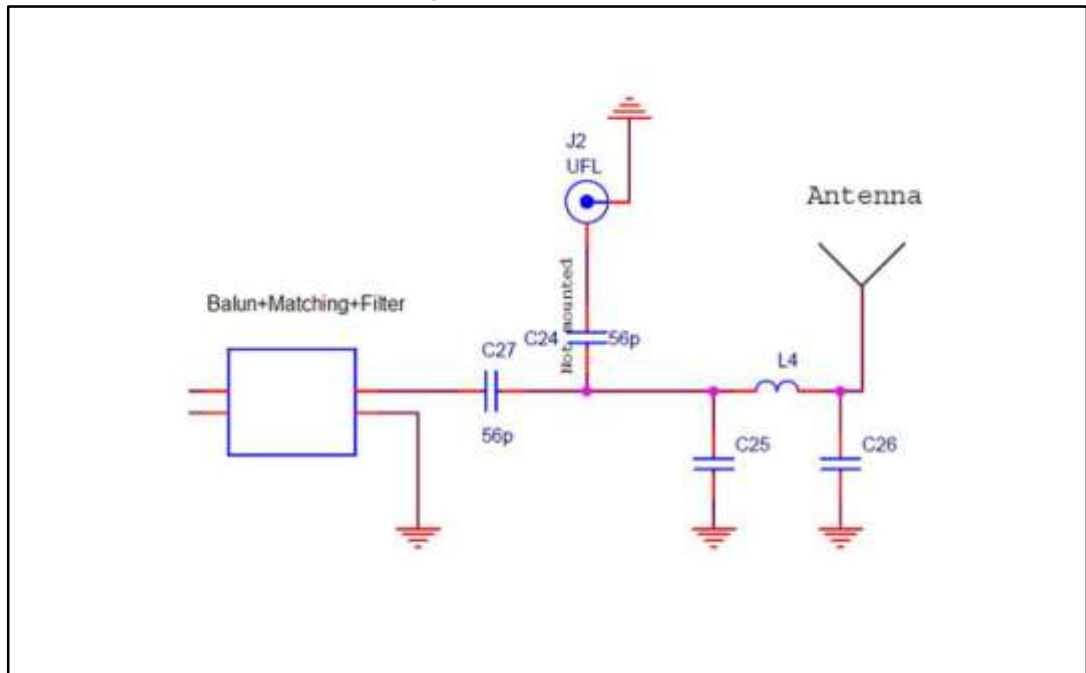
1 Application PCB test points

ST recommends making available a set of test points in order to measure the performance of the device on the customer PCB. Depending on customer PCB constraints, it may not always be possible to add all test points, in which case some tests cannot be performed.

Table 1: Test points

Test point	Function	Details of the test point
Current consumption	Should be added in the PCB to measure BlueNRG-1 current consumption.	In series with the VBAT1,2,3 pins.
Voltage supply	Should be added to measure BlueNRG-1 supply voltages.	To pins: VDD1V2, SMPSFILT1, SMPSFILT2
RF	If the PCB uses an embedded antenna, like a PCB or a chip antenna, it is recommended to add a UFL connector to allow measurement of the RF performance with a spectrum analyzer.	Between the matching network (or balun) and the embedded antenna (see Figure 1: "UFL connector").
ANATEST0, ANATEST1	Pins used for the XTAL_startup measure	Pins: ANATEST0, ANATEST1

Figure 1: UFL connector



2 Power supply test

2.1 Test case specification identifier

SUPPLY_TEST

No specific firmware is needed for this test.

2.2 Test prerequisite

In order to perform this test, you need to add some test points to the platform. Refer to [Section 1: "Application PCB test points"](#) for test pin description.

2.3 Test description

The aim of this test is to ensure that the BlueNRG-1 is Flasher PC application provided within the same package.

2.4 Test procedure

Power up the BlueNRG-1 platform.

Measure the voltage in: VBAT1, 2, 3, VDD1V2, SMPSFILT1, SMPSFILT2.

2.5 Expected results

The measured pin voltage and current should be aligned with the following values if the DC-DC converter ON configuration was chosen.

Table 2: Supply test results

Pin	Expected value
VBAT1,2,3	1.7 – 3.6 V
VDD1V2	1.2 V
SMPSFILT1	Square wave around 1.4 V
SMPSFILT2	1.4 V

If the DC-DC converter OFF configuration was chosen the SMPSFILT1 pin will be floating and the SMPSFILT2 pin will be connected directly to VBAT.

2.6 Note

If some of the measured values are not aligned with the expected values, it is recommended to double-check the integrity of the board's connection.

2.7 Other

N/A

3 Device configuration

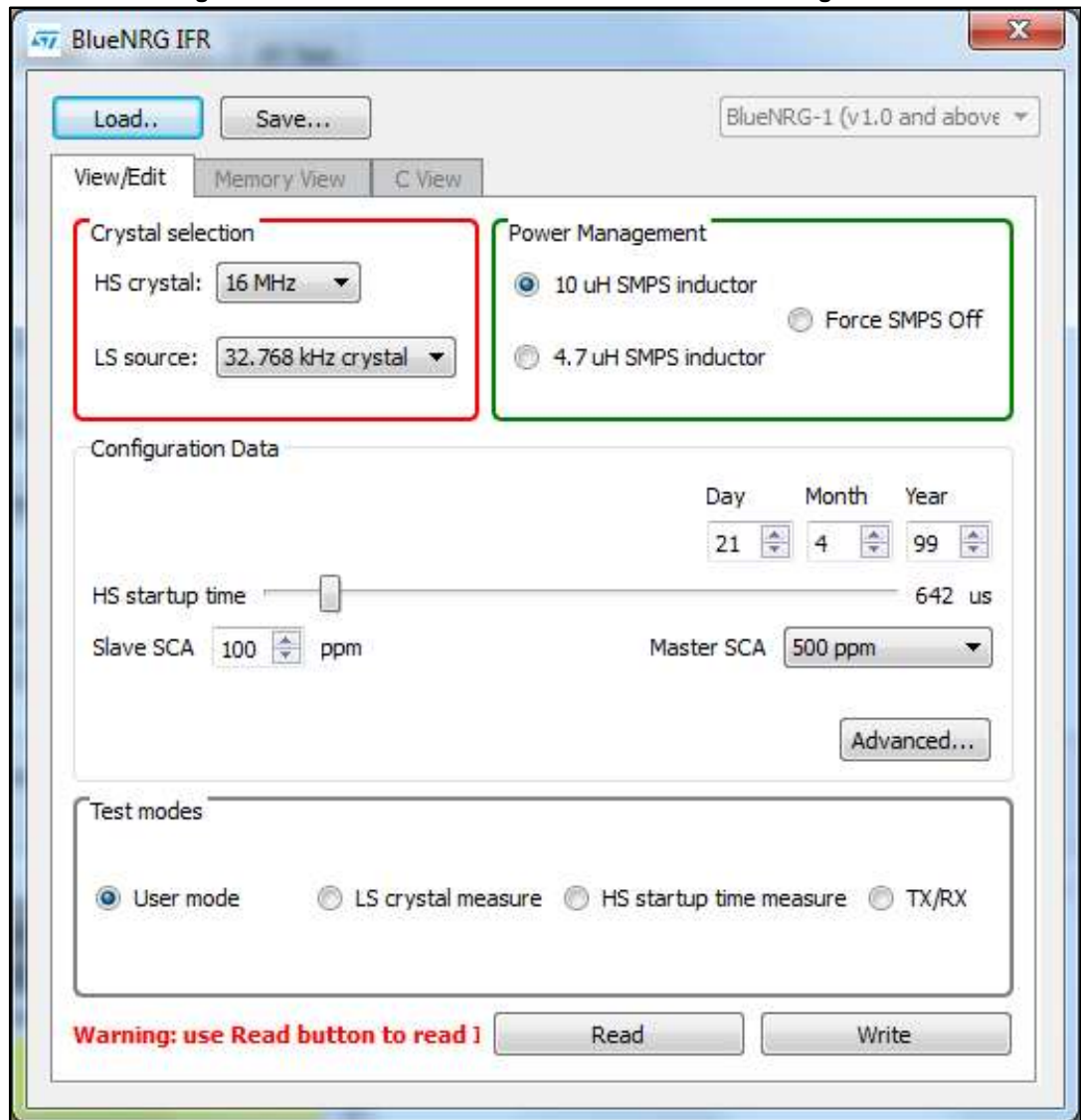
There are some parameters of the BlueNRG-1 device that must be defined and used during software initialization, before the application board is finalized (see [Section 12: "References"#4](#)).

Specifically, they are:

- High speed (HS) crystal (16 or 32 MHz).
- Low speed oscillator source (32 kHz or the internal Ring Oscillator).
- Power Management options (SMPS inductor or SMPS off configuration).
- Change HS startup time parameter from 512 μ s to 1953 μ s.
- Sleep clock accuracy.
- LS crystal period and frequency.

The device configuration parameters can also be set using the BlueNRG GUI PC application available on BlueNRG GUI SW package (STSW-BNRGUI).

Figure 2: BlueNRG GUI IFR tool used for the device configuration



3.1 HS_Startup_Time: Test case specification identifier

XTAL_startup_TEST

3.2 Test prerequisite

The user platform should have the test points for the pins ANATEST0 and ANATEST1 (see [Table 1: "Test points"](#)).

3.3 Test description

The HS_Startup_Time parameter is important because it permits minimization of the current consumption, but to do this a measurement of the startup time of the adopted crystal must be performed (XTAL_startup). A value that is too short prevents the BlueNRG-1 from correctly sending/receiving packets.

3.4 Test setup

3.4.1 Hardware

An oscilloscope is required for this test.

3.4.2 Software

ST BlueNRG GUI and DTM binary file loaded in BlueNRG-1.

3.5 Test procedure

Tick the checkbox present in the BlueNRG IFR tool in the BlueNRG GUI to enable the startup time test signals. Set the HS Startup time parameter to the maximum value and program this value on the device by selecting the WRITE button.

Put two scope probes on test points ANATEST0 and ANATEST1.

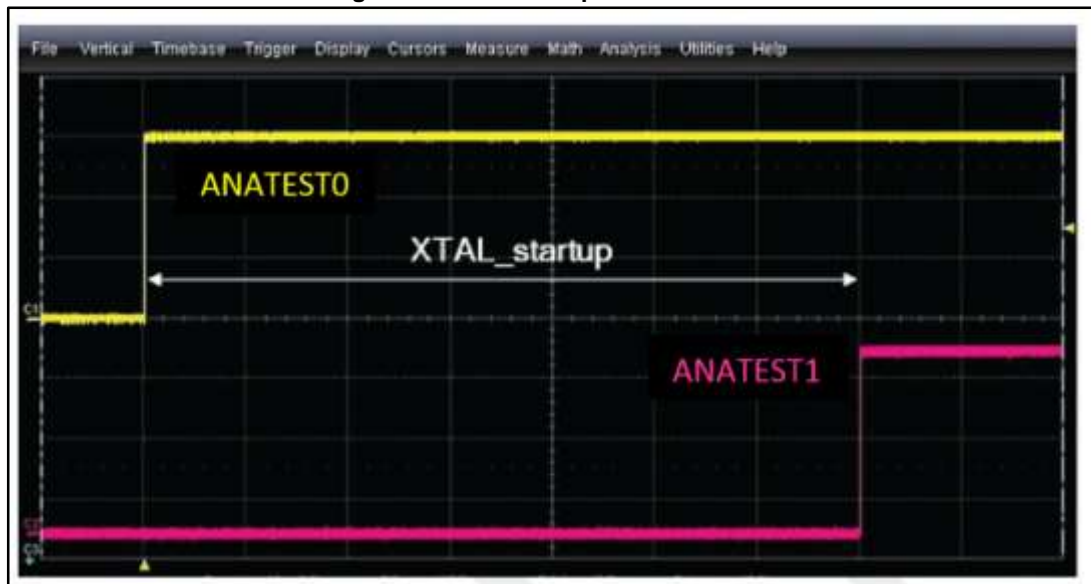
Set the BlueNRG-1 in advertising mode, using these commands with the BlueNRG GUI:
ACI_GATT_INIT

```
ACI_GAP_INIT(Role = Peripheral)
ACI_GAP_SET_DISCOVERABLE(Advertising_Type=0x00,
                          Advertising_Interval_Min=0x0020,
                          Advertising_Interval_Max=0x0020,
                          Own_Address_Type=0x01,
                          Advertising_Filter_Policy=0x03)
```

The time between the rising edge on ANATEST0 and rising edge on ANATEST1 is the time the crystal oscillator takes to start (see [Figure 3: "XTAL_startup measurement"](#)).

Since this time may have a great variation in some conditions, especially when the crystal is kept off for around 20 ms, several measurements must be taken using an advertising interval of 20 ms (a good number of measurements is 180000, which correspond to 1 hour of test). Only the maximum measured value must be considered.

Figure 3: XTAL_startup measurement



3.6 Expected results

The maximum measured value must be compensated in order to consider the variations of the power supply, temperature and the crystal tolerance, by multiplying the value with some specific coefficients:

- 20% : to take in account the effect of power supply variations from 1.7 to 3.6 Volts
- 10% : to take in account the effect of temperature variations within the related operating range
- 30%: to take in account the effect of crystal motional inductance tolerance. It is strongly recommended to use a crystal with a motional inductance tolerance less than 20%.

As consequence, the compensated value is calculated using this formula:

$$XTAL_startup = XTAL_startup_measured * 1.2 * 1.1 * 1.3 = 1.716 * XTAL_startup_measured$$

The `XTAL_startup_measured` is the maximum measured value as described on previous Section [Section 3.5: "Test procedure"](#).

The first coefficient (1.2) can be omitted if the test is performed at the minimum operative voltage.

Finally, to find the `HS_STARTUP_TIME` value that must be set up in the device configuration parameters, use this formula:

$$HS_STARTUP_TIME = 110 \mu s + XTAL_startup$$

3.7 Note

Examples:

$$XTAL_startup_measured = 300 \mu s \rightarrow HS_STARTUP_TIME = 625 \mu s$$

$$XTAL_startup_measured = 700 \mu s \rightarrow HS_STARTUP_TIME = 1311 \mu s$$

3.8 Other

N/A.

4 XTAL centering test

The BlueNRG-1 integrates a low-speed frequency oscillator (LSOSC) and a high-speed (16 MHz or 32 MHz) frequency oscillator (HSOSC).

The low frequency clock is used in low power mode and can be supplied either by a 32.7 kHz oscillator that uses an external crystal or by a ring oscillator with maximum ± 500 ppm frequency tolerance, which does not require any external components.

The primary high frequency clock is a 16 MHz or 32 MHz crystal oscillator.

The frequency tolerance of the high-speed crystal oscillator must be below ± 50 ppm.

The BlueNRG-1 device, as with all RF systems, is highly dependent on accurate clocks for correct operation. A deviation in clock frequency is directly reflected as a deviation in radio frequency, and this can degrade RF performance, violate legal requirements or in the worst case lead to a non-functioning system.

For these reasons the crystal frequency must be centered, and the easiest way to find the optimum load capacitor values for a given circuit and layout is through experimentation.

4.1 Test case specification identifier

XTAL_center_TEST

4.2 Test prerequisite

For this test, the UFL connector (see [Table 1: "Test points"](#)) is not mandatory.

4.3 Test description

For the reasons previously explained, the crystal frequency must be centered, and the easiest way to find the optimum load capacitor values for a given circuit and layout is through experimentation. The radio can be set to put out a constant carrier at a given frequency.

By measuring the output frequency with a spectrum analyzer, the offset can easily be found.

4.4 Test setup

4.4.1 Hardware

A spectrum analyzer is required for this test.

4.4.2 Software

ST BlueNRG GUI and DTM binary file loaded in BlueNRG-1.

4.5 Test procedure

The following procedure is valid for the high-speed oscillator (16 MHz or 32 MHz):

Connect the BlueNRG-1 board to the spectrum analyzer through an RF cable if it is equipped with an UFL connector, otherwise plug a 2.4 GHz antenna into the input port of the instrument.

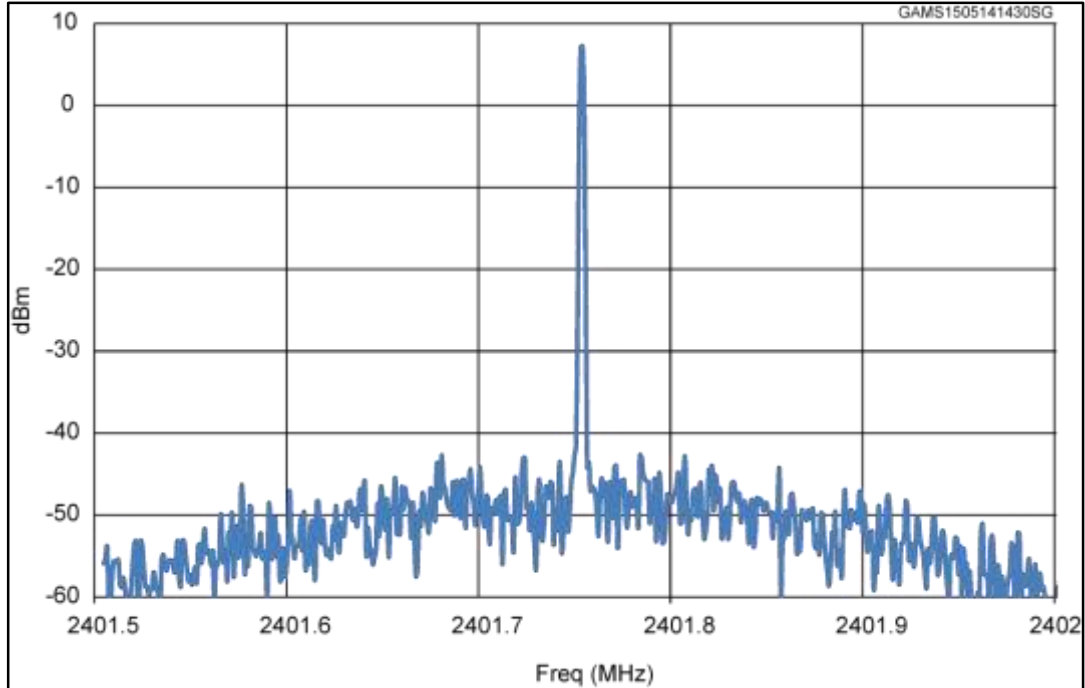
Power up the BlueNRG-1 platform.

Set the spectrum analyzer to: Res BW = 1 kHz, SPAN = 500 kHz (see [Figure 4: "Frequency tone at Ch0 for the XTAL center test"](#)).

Generate a carrier wave tone at Ch0 (freq. 2.401750 GHz) using the BlueNRG GUI, RF Test window, Start Tone button and selecting TX Frequency as 2402 Mhz, Channel 0 (a tone can be emitted at $f = 2402 + k \cdot 2 - 0.250$ MHz, with $k = 0$ to 39).

The difference between the desired tone and the measured tone is the frequency offset.

Figure 4: Frequency tone at Ch0 for the XTAL center test



Same results can be achieved by directly using the ACI command: ACI_HAL_TONE_START.

4.6 Expected results

The offset limit is (as reported in point 1 [Section 12: "References"](#)):

$$|\text{Offset}| < 50 \text{ kHz}$$

If DUT freq > 2.4018 GHz → increase XTAL caps

If DUT freq < 2.4017 GHz → decrease XTAL caps.

4.7 Note

N/A.

4.8 Other

N/A.

5 LSOSC centering test

The LSOSC is used to have a reference time clock. The advantage of using the external 32.768 kHz clock is that it consumes less power than internal RO and it is more accurate (50 ppm). This test permits to center its oscillator frequency, changing the crystal capacitance.

5.1 Test case specification identifier

LSOSC_center_TEST

5.2 Test prerequisite

For this test, a test point in the pin 14 (ANATEST1) is required.

5.3 Test description

There is a way, using the IFR tool of the BlueNRG GUI, to put out the LSOSC signal in the pin 14.

By measuring its frequency with an oscilloscope, the frequency offset can easily be measured.

5.4 Test setup

5.4.1 Hardware

An oscilloscope is required for this test.

5.4.2 Software

ST BlueNRG GUI.

5.5 Test procedure

Connect an oscilloscope's probe in the pin 14 (ANATEST1) test point. Power up the BlueNRG-1 platform.

Set the scope to capture a consistent number of 32 kHz waveform periods (for example 64 cycles, so set the time base at 200us). In this way, the influence of the jitter in the measure is minimized.

In the IFR tool of the GUI make a "Read" of the current IFR configuration, then tick the check-box "LS crystal measure" and then make a "Write" operation.

Now a power cycle is required to let the new IFR be operative.

At this point, the 32.768 kHz waveform will be visible on the oscilloscope screen.

Perform the measurement of the frequency: the difference between the target value ($f=32.768$ kHz) and the measured one is the frequency offset Δf .

5.6 Expected results

If DUT freq > 32.768 kHz → increase XTAL caps

If DUT freq < 32.768 kHz → decrease XTAL caps

To find the oscillator ppm use the formula:

Where:

$$\text{ppm} = \frac{\Delta f}{f} 10^6$$

Δf = offset

f = 32.768 kHz

Add to the found ppm value the one declared in the adopted crystal datasheet.

This final value must be used in the Slave SCA and Master SCA fields when BTLE stack is initialized.

5.7 Note

N/A.

5.8 Other

N/A.

6 Output power test

6.1 Test case specification identifier

OUTPUT_TESTS

6.2 Test prerequisite

For this test the UFL or SMA connector is mandatory.

6.3 Test description

The aim of this test is verification of the Tx output power level and the step linearity.

6.4 Test setup

6.4.1 Hardware

A spectrum analyzer is required for this test.

6.4.2 Software

ST BlueNRG GUI and DTM binary file loaded in BlueNRG-1.

6.5 Test procedure

Connect the BlueNRG-1 board to the spectrum analyzer through an RF cable. Set the spectrum analyzer to: Res BW = 100 kHz, SPAN = 500 kHz.

Power up the BlueNRG-1 platform.

Generate a carrier wave tone at Ch0 (freq. 2.401750 GHz) using the BlueNRG GUI, RF Test window:

- Check High Power to use BlueNRG-1 in High Power mode
- For the step linearity of the Tx output power, select power level to 0x06
- Click on Start Transmitter button to generate a carrier wave

Same results can be achieved by directly using the ACI commands:

- ACI_HAL_SET_TX_POWER_LEVEL (En_High_Power = 0x01, PA_Level: 0x06).
- ACI_HAL_TONE_START (a tone can be emitted at $f=2402 + k*2 - 0.250$ MHz, with $k=0$ to 39)

6.6 Expected results

With PA_level=0x07: around 8 dBm

With PA_level = 0x06: around 4 dBm

6.7 Note

The results are significantly influenced by the matching network performances. The user may need to tune it to obtain maximum performance.

6.8 Other

N/A

Figure 5: Output power measurement in with PA_level 7

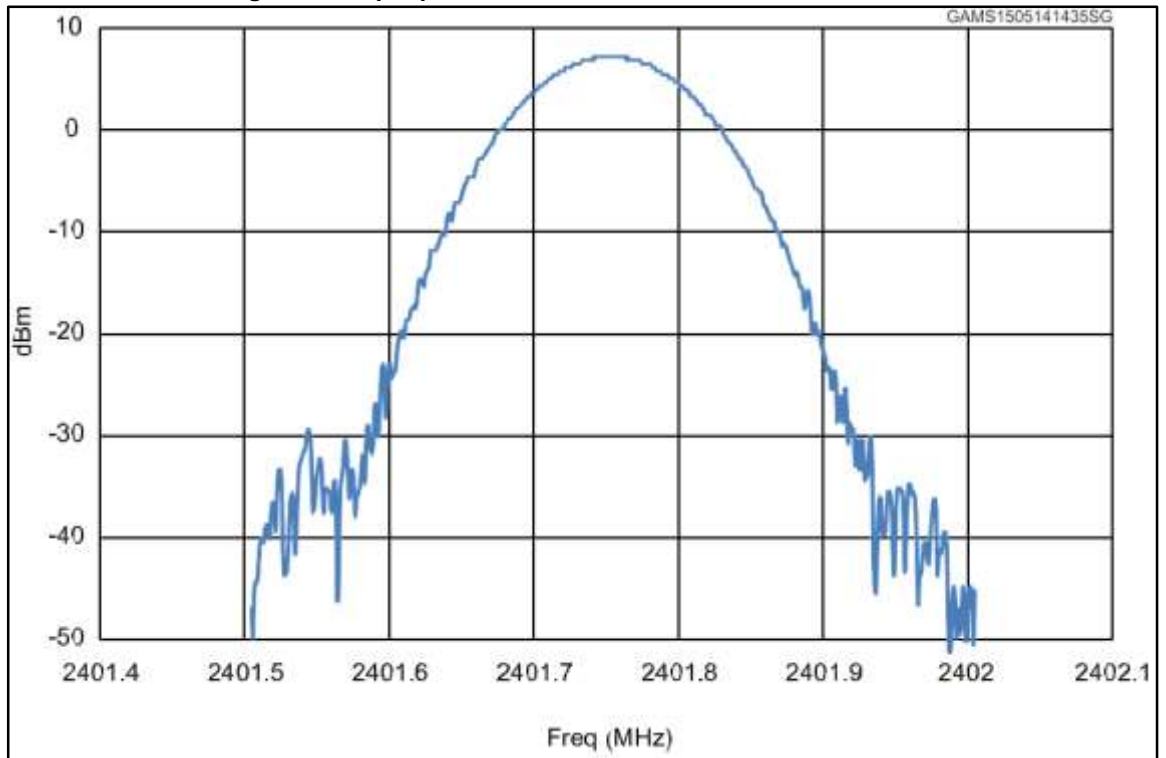
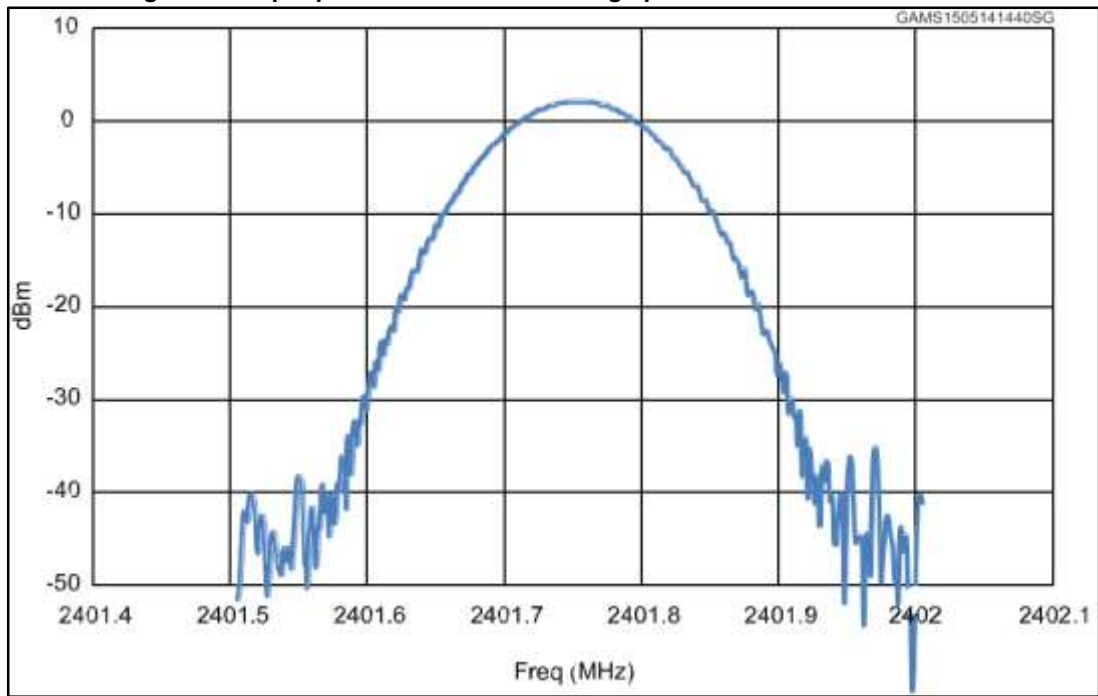


Figure 6: Output power measurement in High power mode with PA_level 6



7 Packet exchange test

7.1 Test case specification identifier

PACKET_TEST

7.2 Test prerequisite

In order to perform these tests, you need a BlueNRG-1 development platform as a master and the DUT board as a slave.

7.3 Test description

The aim of this test is to verify that the DUT board is able to send and receive packets correctly.

7.4 Test setup

7.4.1 Hardware

No instruments required.

7.4.2 Software

ST BlueNRG GUI and DTM binary file loaded in BlueNRG-1.

7.5 Test procedure

Power up the BlueNRG-1 platform (Rx) and the DUT board that acts as Tx and ensure that antenna are plugged in.

Follow these steps for starting packet exchange test:

In the GUI related to RX BlueNRG-1 device,

- Go to RF Test window, RECEIVER section
- Set RX frequency
- Click on "Start Receiver" Button, to start Receiver Test

In the GUI related to TX device,

- Go to RF Test window, TRANSMITTER section
- Set TX power
- Set TX Frequency
- Set Length of Data to 0x25
- Set Packet Payload format
- Click on "Start Transmitter" Button, to start Transmitter Test

In the GUI related to TX device:

- Click on "Stop Transmitter" button. The number of transmitted packets are displayed on #Packet Transmitted field.

In the GUI related to Rx BlueNRG-1 device

- Click on "Stop Receiver" button. The number of received packets are displayed on #Packet Received field.

- In the PER section, insert the number of transmitted packet from TX device in the Packet Transmitted field (read this value from TRANSMITTER section in the GUI related to TX device)
- The PER (Packet Error Rate) value is showed in the Packet Error Rate field

Same results can be achieved by directly using the ACI commands:

- Start Rx on DUT: HCI_LE_RECEIVER_TEST
- Make the Tx board send packets: HCI_LE_TRANSMITTER_TEST, with the length of test data: 0x25
- Stop test on Tx board: HCI_LE_TEST_END
- Send this command in order to determine the number of packets sent by the Tx: ACI_HAL_LE_TX_TEST_PACKET_NUMBER
- Stop test on DUT: HCI_LE_TEST_END
- This returns Y as the number of received packets.

7.6 Expected results

The number of packets received over-the-air should be equal to the number of packets sent by the Tx board.

7.7 Note

N/A.

7.8 Other

N/A.

8 Sensitivity test

8.1 Test case specification identifier

SENSITIVITY_TEST

8.2 Test prerequisite

It is possible to adopt two different hardware configurations for this test:

1. A signal generator (ex. the Agilent E4438C, controlled through a GPIB interface) as Tx and the BlueNRG-1 board (DUT) connected as shown in [Figure 1: "UFL connector"](#).
2. ST BlueNRG-1 demo kit as Tx device and BlueNRG-1 board (DUT).

8.3 Test description

The aim of this test is to verify the sensitivity level of the DUT board.

8.4 Test setup

8.4.1 Hardware

Tx: Agilent E4438C signal generator or ST BlueNRG-1 demo kit

Rx: DUT application board to test (see [Figure 1: "UFL connector"](#)).

8.4.2 Software

ST BlueNRG GUI and DTM binary file loaded in BlueNRG-1.

8.5 Test procedure

Two procedures can be used.

8.5.1 Signal generator & DUT board

The sensitivity can be evaluated by performing the following steps:

1. Connect the instrument and the DUT with an RF cable (with no significant loss).
2. Start Rx on DUT: on RF Test window click on Start Receiver button
3. Make the generator send X packets (well formatted as described in "Direct Test Mode", Vol. 6, Part F, and "Host Controller Interface Functional Specification", VOL. 2, Part E, in point 3 [Section 12: "References"](#))
4. Stop test on DUT: on RF Test window click on Stop Receiver button

On Packet Received tab there is the number of received packets. PER is 1-Y/X.

If PER is below 0.308 (30.8%), go back to step 2 and decrease the power of the transmitter by one step. If PER goes above 0.308, then the level of power emitted by the equipment in the previous test is the sensitivity of the receiver. The algorithm can be made more accurate by reducing the power level step when it is close to the sensitivity level.

Same results can be achieved by directly using the ACI commands:

1. Connect the instrument and the DUT with an RF cable (with no significant loss).
2. Start Rx on DUT: HCI_LE_RECEIVER_TEST

3. Make the generator send X packets (well formatted as described in "Direct Test Mode", Vol. 6, Part F, and "Host Controller Interface Functional Specification", VOL. 2, Part E, in point 3 [Section 12: "References"](#))
4. Stop test on DUT: HCI_LE_TEST_END

This returns Y as the number of received packets. PER is $1-Y/X$.

If PER is below 0.308 (30.8%), go back to step b and decrease the power of the transmitter by one step. If PER goes above 0.308, then the level of power emitted by the equipment in the previous test is the sensitivity of the receiver.

The algorithm can be made more accurate by reducing the power level step when it is close to the sensitivity level.

8.5.2 ST BlueNRG-1 demo kit & DUT board

In this case, the previous procedure changes in the following way:

1. Connect the RF input/output of the two boards, DUT and ST BlueNRG-1 boards, by using a variable attenuator.
2. In the GUI related to DUT RX BlueNRG-1 device,
 - Go to RF Test window, RECEIVER section
 - Set RX frequency
 - Click on "Start Receiver" Button, to start Receiver Test
3. In the GUI related to TX device,
 - Go to RF Test window, TRANSMITTER section
 - Set TX power
 - Set TX Frequency
 - Set Length of Data to 0x25
 - Set Packet Payload format
 - Click on "Start Transmitter" Button, to start Transmitter Test
4. In the GUI related to TX device:
 - Click on "Stop Transmitter" button. The number of transmitted packets are displayed on #Packet Transmitted field.
5. In the GUI related to DUT RX BlueNRG-1 device:
 - Click on "Stop Receiver" button. The number of received packets are displayed on #Packet Received field.
6. In the PER section, insert the number of transmitted packet from TX device in the Packet Transmitted field (read this value from TRANSMITTER section in the GUI related to TX device)
7. The PER (Packet Error Rate) value is showed in the Packet Error Rate field

If PER is below 0.308 (30.8%), go back to step 2 and increase the value of the attenuation. If PER goes above 0.308, then the level of power received by the DUT in the previous test is the sensitivity of the receiver. It is very important to measure correctly or estimate the power received by the DUT (e.g. by the use of a tone instead of a modulated signal).

Moreover, in order to reduce the level of the signal received over-the-air by the DUT, the ST BlueNRG-1 demo kit should use the minimum output power. Performing the measurements inside an anechoic chamber will also give more accurate results.

Same results can be achieved by directly using the ACI commands:

1. Connect the RF input/output of the two boards, DUT and STM BlueNRG-1 boards, by using a variable attenuator.
2. Start Rx on DUT: HCI_LE_RECEIVER_TEST
3. Make the STM BlueNRG-1 board send packets: HCI_LE_TRANSMITTER_TEST, with the length of test data: 0x25
4. Stop test on STM BlueNRG-1 board: HCI_LE_TEST_END

5. Send a further command to determine the number of packets sent by the STM BlueNRG-1 board: ACI_HAL_LE_TX_TEST_PACKET_NUMBER
6. Stop test on DUT: HCI_LE_TEST_END

This returns Y as the number of received packets. PER is $1 - Y/X$.

If PER is below 0.308 (30.8%), go back to step 2 and increase the value of the attenuation. If PER goes above 0.308, then the level of power received by the DUT in the previous test is the sensitivity of the receiver.

8.6 Expected results

The expected value should be a few dB from the value reported in the datasheet. If it is not, the reason could be related to the matching network.

8.7 Note

Since the sensitivity test is very time-consuming, ST can provide specific software for both hardware configurations in order to implement an automatic procedure.

8.8 Other

N/A.

9 Power consumption in advertising mode

9.1 Test case specification identifier

CURRENT_TEST

9.2 Test prerequisite

In order to perform this test the platform must be provided with the test points in series with the Vbat1, 2, 3 pins (see [Table 1: "Test points"](#)).

9.3 Test description

The aim of this test is to verify that the BlueNRG-1 current consumption profile during the advertising is aligned with the simulated value (for simulated values use the BlueNRG Current Consumption Estimation Tool (STSW-BNRG001) available on www.st.com).

9.4 Test setup

9.4.1 Hardware

Agilent N6705B power analyzer or an oscilloscope.

9.4.2 Software

ST BlueNRG GUI.

9.5 Test procedure

Connect the power analyzer in series to the Vbat pins in the BlueNRG-1. If it is not available, use a 10 Ohm resistor to sense the current, connecting two probes to it.

Power up the BlueNRG-1 platform and load a firmware which puts the device in advertising mode, e.g. Sensor Demo.

Capture the current waveform.

9.6 Expected results

The average current should be as reported here (see [Figure 7: "Typical current profile during an advertising event"](#)):

Avg. current = approx. 6 mA

Sleep current = approx. 2 μ A (see [Section 12: "References"#1](#))

These values are significantly influenced by the device configuration parameters, such as the HS_Startup_Time, the Stack Mode and the 32 kHz crystal (external or internal ring oscillator)

Figure 7: Typical current profile during an advertising event



9.7 Note

N/A.

9.8 Other

N/A.

10 RF tests for certification

The tests described in this application note should be used to check the basic functionality of the BlueNRG-1 device on prototype boards.

Before Bluetooth trademark can be used on BlueNRG-1 devices, the company must complete the Bluetooth Compliance Program, i.e. the board must be qualified and listed.

Since BlueNRG-1 is an already qualified product, a board that uses BlueNRG-1 device does not have to rerun all the Bluetooth tests. However, when using BlueNRG-1 in a new RF design, the RF-PHY layer still must be tested.

These are the RF tests that have to be performed (RF-PHY.TS/4.2.0):

- TP/TRM-LE/CA/BV-01-C [Output power at NOC]
- TP/TRM-LE/CA/BV-02-C [Output power at EOC]
- TP/TRM-LE/CA/BV-03-C [In-band emissions at NOC]
- TP/TRM-LE/CA/BV-04-C [In-band emissions at EOC]
- TP/TRM-LE/CA/BV-05-C [Modulation Characteristics]
- TP/TRM-LE/CA/BV-06-C [Carrier frequency offset and drift at NOC]
- TP/TRM-LE/CA/BV-07-C [Carrier frequency offset and drift at EOC]
- TP/RCV-LE/CA/BV-01-C [Receiver sensitivity at NOC]
- TP/RCV-LE/CA/BV-02-C [Receiver sensitivity at EOC]
- TP/RCV-LE/CA/BV-03-C [C/I and Receiver Selectivity Performance]
- TP/RCV-LE/CA/BV-04-C [Blocking Performance]
- TP/RCV-LE/CA/BV-05-C [Intermodulation Performance]
- TP/RCV-LE/CA/BV-06-C [Maximum input signal level]
- TP/RCV-LE/CA/BV-07-C [PER Report Integrity]

Moreover, depending on the country of use, an RF product must be compliant with one or more standards before it can be sold. In particular, Bluetooth Low Energy products, which operate in the unlicensed ISM band at 2.4 GHz, must be compliant to:

- FCC Part 15.205, 15.209, 15.247 in North America
- ETSI EN 300 328 in Europe
- ARIB STD-T66 in Japan

Bluetooth LE tests can be manually performed, but instruments exist that simplify and automate the testing process.

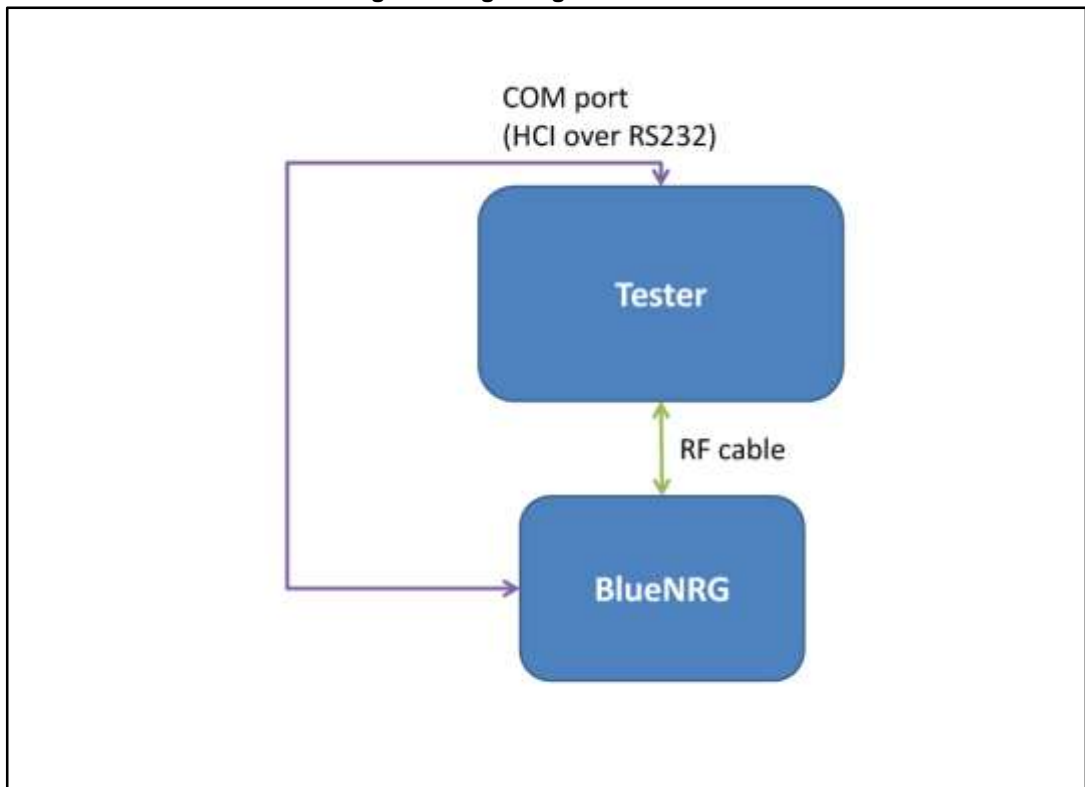
Normally this kind of instruments can operate in two modes:

- Signaling mode
- Non-signaling mode

10.1 Signaling mode

In this mode, the instrument can autonomously perform the tests. The DUT (Device Under Test) must be connected to the instrument with an RF cable. Moreover, the DUT has to be connected to one instrument's port in order to be controlled by the instrument itself (to start/stop test and receive feedback from DUT). BlueNRG-1 supports the Direct Test Mode over HCI, which allows testing Low Energy PHY layer (see Bluetooth specification, Core v4.1, Vol. 6, Part F: Direct Test Mode).

Figure 8: Signaling mode RF tests

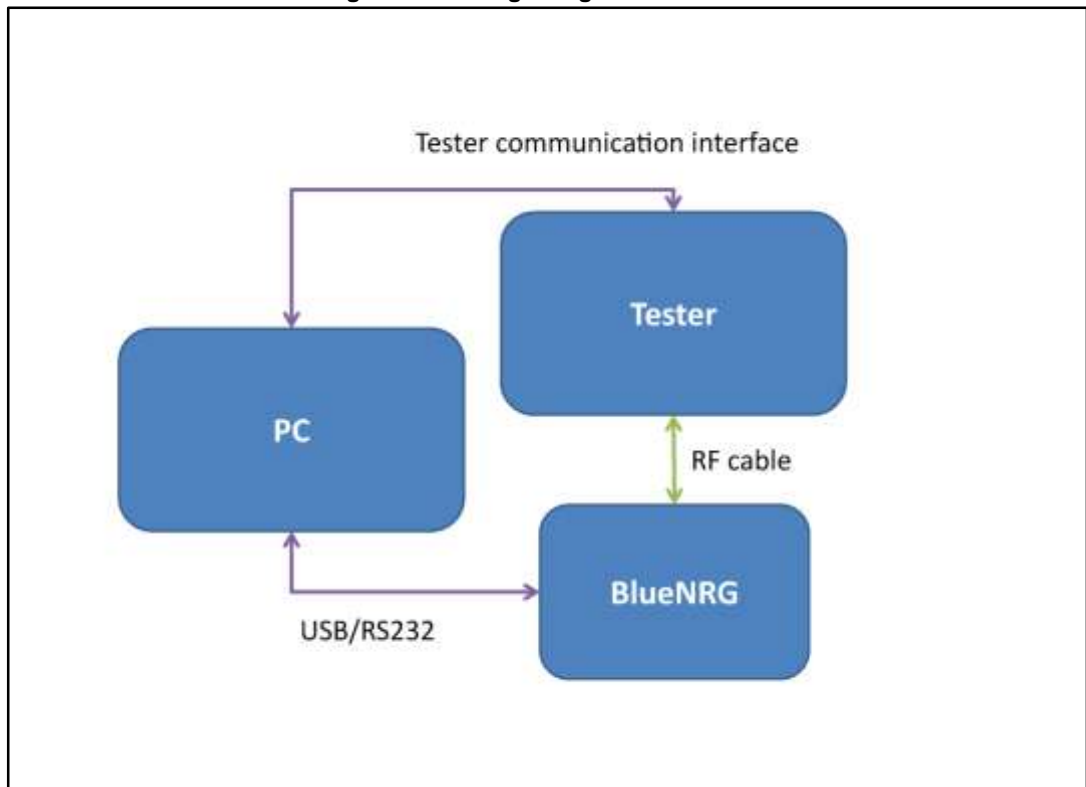


On the test equipment, the serial port for communication with the DUT is typically an RS232 interface. BlueNRG-1 is already provided with a UART interface.

10.2 Non-signaling mode

In non-signaling mode a third entity (e.g. a PC) controls both DUT and Test instrument at the same time. Typically, the instrument can be controlled by using proprietary commands. The native communication interface of BlueNRG-1 is UART and this interface can be connected to PC via a serial to USB converter.

Figure 9: Non-signaling mode RF tests



11 RF tests for boards manufacturing

Once the final board has been designed and sent to production, the manufacturer may want to run some basic tests to be confident that the device is operating correctly. The minimal set of suggested tests is:

- Output power (see [Section 6: "Output power test"](#)) and crystal frequency centering test (see [Section 4: "XTAL centering test"](#))
- Packet exchange test (see [Section 7: "Packet exchange test"](#)).

Some of these tests can also be performed by dedicated instruments, as described in Section 10.1 ([Section 10.1: "Signaling mode"](#)). In this case, a good minimal set of tests to be performed is:

- Output power
- Carrier frequency offset and drift
- Receiver sensitivity

12 References

1. BlueNRG-1 datasheets
2. Bluetooth specification version v4.1
3. BlueNRG-1 development kits user manual
4. BlueNRG GUI SW package (STSW-BNRGUI) user manual (UM2058)

13 Revision history

Date	Version	Changes
29-Jun-2016	1	Initial release.

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